

Fast and accurate cold particle data to maximize your results



Fast data collection and analysis for cold spray and similar processes:

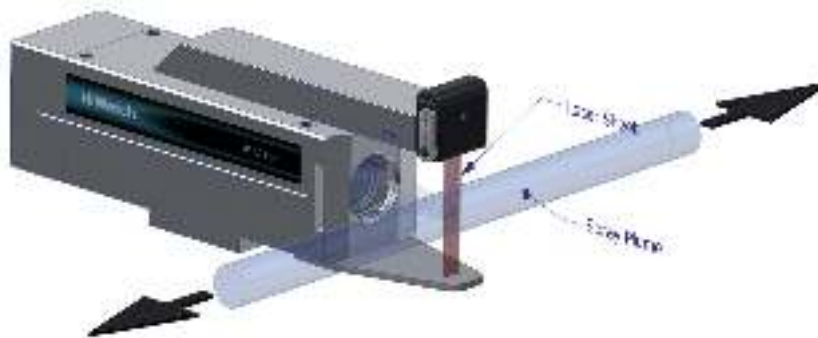
- Optimize coating performance & deposition efficiency
- Offering best control of coating thickness per pass
- Minimizing use of materials and resources and waste to save cost and the environment
- Maximizing your profitability

*Best choice for
fast & easy daily particle
diagnostics and QA*

HiWatch

oseir.com/hiwatch-cs2

HiWatch



HiWatch GS is an easy to use system that can fast collect the important data for making decisions how to optimize your process for best quality, lowest cost and least waste. Due to it's compact size and effective shape it can be installed in a convenient location in the booth where the cold spray gun can be brought for checking the process before spraying any parts.

System features

Measurements	Particle velocity, position, diameter
Measurement area	~ 8x6 mm ²
Measurement depth	~ 1mm
Particle velocity range	0-2000 m/s
Particle diameter range	5-1000 µm
Capture speed	> 10 fps
Camera resolution	1920 x 1200
Dimensions (WxHxD)	60 x 80 x 270 mm
Weight	1.3 kg
Control PC	Win10 Pro, Core i5, 8GB, Gigabit ethernet
Laser wavelength	~800 nm
Laser safety	IEC Class 3B
Cooling	Filtered compressed air

NOTE: values indicated are typical but not absolute. The range may depend on the the process and application.

All measurements are factory calibrated no need for field calibration.

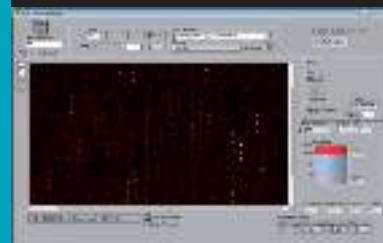


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Informative user interface



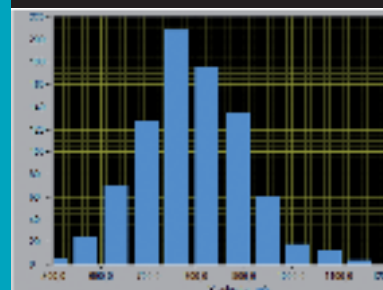
Measured parameters are: particle speed, size, position in the plume, total number of particles in the sample and plume density.

Particle tracking velocimetry



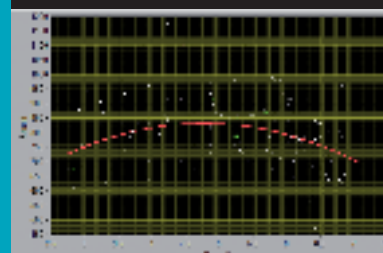
Automatic particle detection and analysis either in real time or post processing from stored images.

Property distributions



Distribution of particle speed, position in the plume and particle size.

Property crossplots



Model fitting between any two measured parameters.